

iEDX-150T

Specification



Item	Details
X-ray tube	Mo/Rh/W/Ag Target(Option), 50kVp, 1mA
Detection System	Si-Pin Diode (Option : SDD, FSDD)
Energy Resolution	Si-Pin Diode : 149eV FWHM at Mn K α / Option : SDD(125eV), FSDD(122eV)
	0.3 Collimator (Option: 0.05, 0.1, 0.2, 0.5, 1mm)
	Capillary Optics 50um
Collimator	Manual / Auto Changing Stage
Detection Element	Ti(22)~U(92)
Sample Type	Solid / Liquid / Powder, Multi-Layer
Size of the sample chamber	660mmX450mmX150mm / 500mmX450mmX150mm
Sample stage moving possible distance	300mmX200mmX150mm / 220mmX200mmX150mm

Item	Details
Size of the sample table	310mm X 260mm
	Auto / Manual Stage Mode
	Plating thickness measurement : General, Rh, Pd, Au, Ag, Sn, Ni
Key Features	Film thickness measurement of multilayer thin films (up to 5 Layer)
Camera Magnification	40~80 x
Safety	3 point interlock
	Excel, PDF / output
Type of Report	Custom form
.,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	
	Film thickness measurement of multilayer thin films (up to 5 Layer)
	Convenient stage control
	Multi-point measurement possible
	RoHS Screening (Option)
Key Benefits	Remote Support by Online
Rey Delients	
	Product screening international environmental regulations
	(RoHS, WEEE, ELV compliant)
	Hazardous material(Cr, Br, Cd, Hg, Pb, Cl, Sb, Sn, S) Screening equipment
	Plating analysis automobile parts, Electronic circuit board(PCB), Such as a capacitor
	Analysis of single-layer, Multi-layer, Alloy plating
Application	Thickness with Composition Ratio can be measure on time in alloy plating